Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/972,229	WEE ET AL.
Examiner	Art Unit
Fleni A Shiferaw	2136

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380	200	12/27/2004	· es

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East Search	12/27/2004	es
NPL: IEEE ((progressive image <in>metadata)<and>(different encryption method<in>metadata))</in></and></in>	5/13/2005	ES